

Hydrogen Peroxide, 30%
CMOS
(Stabilized)



Material No.: 2190-03
Revision No.: 0

Product Specification

| Test | Specification |
|--|---------------|
| Assay (H ₂ O ₂) | 30.0 - 32.0 % |
| Color (APHA) | ≤ 10 |
| Free Acid (μeq/g) | ≤ 0.2 |
| Residue after Evaporation | ≤ 10 ppm |
| Ammonium (NH ₄) | ≤ 3 ppm |
| Chloride (Cl) | ≤ 0.2 ppm |
| Nitrate (NO ₃) | ≤ 2 ppm |
| Phosphate (PO ₄) | ≤ 1 ppm |
| Sulfate (SO ₄) | ≤ 3 ppm |
| Trace Impurities - Aluminum (Al) | ≤ 70.0 ppb |
| Arsenic and Antimony (as As) | ≤ 10.0 ppb |
| Trace Impurities - Barium (Ba) | ≤ 20.0 ppb |
| Trace Impurities - Beryllium (Be) | ≤ 10.0 ppb |
| Trace Impurities - Bismuth (Bi) | ≤ 20.0 ppb |
| Trace Impurities - Boron (B) | ≤ 10.0 ppb |
| Trace Impurities - Cadmium (Cd) | ≤ 10.0 ppb |
| Trace Impurities - Calcium (Ca) | ≤ 50.0 ppb |
| Trace Impurities - Chromium (Cr) | ≤ 20.0 ppb |
| Trace Impurities - Cobalt (Co) | ≤ 10.0 ppb |
| Trace Impurities - Copper (Cu) | ≤ 10.0 ppb |
| Trace Impurities - Gallium (Ga) | ≤ 20.0 ppb |
| Trace Impurities - Germanium (Ge) | ≤ 10.0 ppb |
| Trace Impurities - Gold (Au) | ≤ 10.0 ppb |
| Heavy Metals (as Pb) | ≤ 500.0 ppb |
| Trace Impurities - Iron (Fe) | ≤ 50.0 ppb |
| Trace Impurities - Lead (Pb) | ≤ 10.0 ppb |
| Trace Impurities - Lithium (Li) | ≤ 10.0 ppb |
| Trace Impurities - Magnesium (Mg) | ≤ 10.0 ppb |

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For questions on this Product Specification please contact Technical Services at 855.282.6867 or +1.610.386.1700
Avantor Performance Materials, LLC
100 Matsonford Rd, Suite 200, Radnor, PA 19087. U.S.A. Phone 610.386.1700

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| Trace Impurities - Manganese (Mn) | ≤ 10.0 ppb |
| Trace Impurities - Molybdenum (Mo) | ≤ 10.0 ppb |
| Trace Impurities - Nickel (Ni) | ≤ 10.0 ppb |
| Trace Impurities - Niobium (Nb) | ≤ 10.0 ppb |
| Trace Impurities - Potassium (K) | ≤ 600.0 ppb |
| Trace Impurities - Silicon (Si) | ≤ 100.0 ppb |
| Trace Impurities - Silver (Ag) | ≤ 10.0 ppb |
| Trace Impurities - Sodium (Na) | ≤ 100.0 ppb |
| Trace Impurities - Strontium (Sr) | ≤ 10.0 ppb |
| Trace Impurities - Tantalum (Ta) | ≤ 10.0 ppb |
| Trace Impurities - Thallium (Tl) | ≤ 50.0 ppb |
| Trace Impurities - Tin (Sn) | 190.0 - 500.0 ppb |
| Trace Impurities - Titanium (Ti) | ≤ 10.0 ppb |
| Trace Impurities - Vanadium (V) | ≤ 10.0 ppb |
| Trace Impurities - Zinc (Zn) | ≤ 50 ppb |
| Trace Impurities - Zirconium (Zr) | ≤ 10.0 ppb |
| Particle Count - 0.2 µm and greater | ≤ 1175 par/ml |
| Particle Count - 0.5 µm and greater | ≤ 100 par/ml |

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For Microelectronic Use

Packaging Site: Paris Mfg Ctr & DC


Jamie Ethier
Vice President Global Quality

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